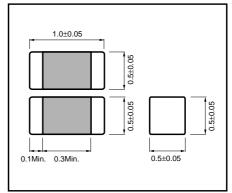
Multi-layer ceramic chip capacitors

MCH15 (1005 (0402) size, chip capacitor)

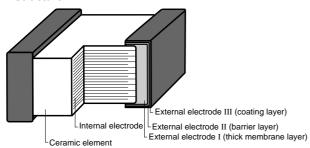
Features

- 1) Small size (1.0 x 0.5 x 0.5 mm) makes it perfect for lightweight portable devices.
- 2) Comes packed either in tape to enable automatic mounting or in bulk cases.
- 3) Precise uniformity of shape and dimensions facilitates highly efficient automatic mounting.
- 4) Barrier layer and end terminations to improve solderability.

●External dimensions (Units : mm)



Structure

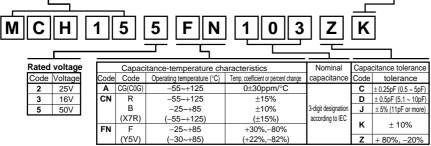


Product designation

Code	Product thickness	Packaging specifications	Reel	Basic ordening unit (pcs.)
K	0.5mm	Paper tape (width 8 mm, pitch 2 mm)	φ180mm (7in.)	10,000
L	0.5mm	Paper tape (width 8 mm, pitch 2 mm)	φ330mm (13in.)	50,000
С	0.5mm	Bulk case	_	50,000

Reel (\$\phi180\$, \$\phi330mm\$): compatible with EIAJ ET-7200A Bulk case: compatible with EIAJ ET-7201A

No. Packaging style



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Capacitance range

For thermal compensation

Part number MCH15					
Capacitance (pF)	Temperature characteristics	A (CG) (C0G)			
Сарасканое (рг)	Rated voltage (V) Tolerance	50V			
0.5 0.75 1					
1.2 1.3 1.5					
1.6 1.8					
2 2.2 2.4	C (± 0.25pF)				
2.7 3 3.3					
3.6 3.9 4					
4.3 4.7 5					
5.1 5.6 6					
6.2 6.8 7	D (± 0.5pF)				
7.5 8 8.2	<i>D</i> (± 0.0pi)				
9 9.1 10					
11 12 13					
15 16 18					
20 22 24	J (± 5%)				
27 30 33					
36 39 43					

Part n	MCH15	
Capacitance (pF)	Temperature characteristics	A (CG) (C0G)
Оправлание (рг.)	Rated voltage (V) Tolerance	50V
47		
51 56		
62 68	<u> </u>	
75	•	
82 91 100		
110		
120 130		
150 160 180	J (± 5%)	
200 220 240		
270 300 330		
360 390 430		
470 510 560		

Product thickness (mm) 0.5 ± 0.05

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High dielectric constant

Part number		MCH15				
Occasion (5	Temperature characteristics	CN (R) (B) (X7R)		FN (F) (Y5V)		
Capacitance (pF)	Rated voltage (V)	50V	16V	50V	25V	16V
	Tolerance	K (±10%)		Z (+80, -20%)		
220						
270 330						
390						
470						
560						
680 820						
1,000						
1,200						
1,500 1,800						
2,200						
2,700						
3,300						
4,700						
5,600						
6,800 8,200						
6,200 10,000 (0.01μF)						
12,000						
15,000						
18,000 22,000						
27,000						
33,000						
39,000 47,000						
56,000						
68,000						
82,000						
100,000 (0.1μF) 120,000						
150,000						
180,000						
220,000						
270,000 330,000						
390,000						
470,000						
560,000						

Product thickness (mm) 0.5 ± 0.05

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Characteristics

Class 1 (For thermal compensation)

	Temperature characteristics			
Item		A (CG) (C0G)	Test methods/conditions (based on JIS C 5102)	
Operating temperature		−55°C ~ 125°C		
Nominal capacitance (C)		Must be within the specified tolerance range.	Based on paragraph 7.8 and paragraph 9 Measured at room temperature and standard humidity,	
Dissipation factor (tanδ)		100/(400+20C)% or less: Less than 30 pF 0.1% or less : 30 pF or larger	1000pF or less Measurement frequency: 1 ± 0.1MHz Measurement voltage: 1 ± 0.1Vrms. Over 1000pF Measurement frequency: 1 ± 0.1kHz Measurement voltage: 1 ± 0.1Vrms.	
Insulation resistance (IR)		10,000M Ω or 500M $\Omega \cdot \mu F$, whichever is smaller	Based on paragraph 7.6 Measurement is made after rated voltage is applied for 60 ±	
Withstanding voltage		The insulation must not be damaged.	Based on paragraph 7.1 Apply 300% of the rated voltage for 1 to 5s then measure.	
Temperature ch	haracteristics	Within 0 ± 30ppm/°C	The temperature coefficients in table 12, paragraph 7.12 are calculated at 20°C and high temperature.	
Terminal adherence		No detachment or signs of detachment.	Based on paragraph 8.11. 2. Apply 5N for 10 ± 1s in the direction indicated by the arrow. Pressure (5) Capacitor	
	Appearance	There must be no mechanical damage.	Chip is mounted to a board in the manner	
Resistance to vibration	Rate of capacitance change	Must be within initial tolerance.	shown on the right, subjected to vibration (type A in paragraph 8.2), and measured	
	Dissipation factor (tanδ)	Must satisfy initial specified value.	24 ± 2 hrs. later.	
Solderability		At least 3/4 of the surface of the two terminals must be covered with new solder.	Based on paragraph 8.13 Soldering temperature: $235 \pm 5^{\circ}\text{C}$ Soldering time : $2 \pm 0.5\text{s}$	
	Appearance	There must be no mechanical damage.		
	Rate of capacitance change	\pm 2.5% or \pm 0.25 pF, whichever is larger.	Based on paragraph 8.14.	
Resistance to soldering	Dissipation factor (tanδ)	Must satisfy initial specified value.	Soldering temperature: 260 ± 5°C	
heat	Insulation resistance	10,000M Ω or 500M $\Omega \cdot \mu F$, whichever is smaller	Soldering time : $5 \pm 0.5s$ Preheating : $150 \pm 10^{\circ}$ C for 1 to 2 min.	
	Withstanding voltage	The insulation must not be damaged.		
	Appearance	There must be no mechanical damage.		
	Rate of capacitance change	\pm 2.5% or \pm 0.25 pF, whichever is larger.	Based on paragraph 9.3	
Temperature cycling	Dissipation factor (tanδ)	Must satisfy initial specified value.	Number of cycles : 5	
	Insulation resistance	10,000M Ω or 500M $\Omega \cdot \mu F$, whichever is smaller	Capacitance measured after 24 ± 2 hrs.	
	Appearance	There must be no mechanical damage.	Based on paragraph 9.9	
Ī	Rate of capacitance change	\pm 7.5% or \pm 0.75 pF, whichever is larger.	Test temperature: 40 ± 2°C Relative humidity: 90% to 95%	
Humidity load test	Dissipation factor (tanδ)	0.5% or less	Applied voltage : rated voltage	
	Insulation resistance	500M Ω or 25M $\Omega \cdot \mu F$, whichever is smaller	Test time : 500 to 524 hrs. Capacitance measured after 24 ± 2 hrs.	
	Appearance	There must be no mechanical damage.	Based on paragraph 9.10	
High-	Rate of capacitance change	\pm 3.0% or \pm 0.3 pF, whichever is larger.	Test temperature: Max. operating temp.	
temperature load test	Dissipation factor (tanδ)	0.3% or less	Applied voltage : rated voltage × 200% Test time : 1,000 to 1,048 hrs.	
ioau iost	Insulation resistance	1,000M Ω or 50M $\Omega \cdot \mu$ F, whichever is smaller	Capacitance measured after 24 ± 2 hrs.	

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Class 2 (High dielectric constant)

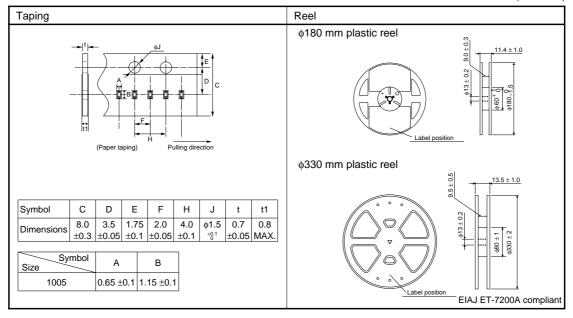
Jass 2 (High die	lectric constant)				
Temperature characteristics		CN (R) (B) (X7R)	FN (F) (Y5V)	Test methods/conditions (based on JIS C 5102)	
Operating temperature		−55°C ~ +125°C	−30°C ~ +85°C		
Nominal capacitance (C)		Must be within the specified tolerance range.		Based on paragraph 7.8	
Dissipation factor (tanδ)		2.5% or less (when rated voltage is 16V: 3.5% or less) (when rated voltage is 16V: 7.5% or less)		Measured at room temperature and standard humidii Measurement frequency: 1 \pm 0.1 kHz Measurement voltage : 1.0 \pm 0.2 Vrms.	
Insulation resistance (IR)		10,000Μ Ω or 500Μ $\Omega \cdot \mu$ F, whichever is smaller		Based on paragraph 7.6 Measurement is made after rated voltage is applied for $60 \pm 5s$.	
Withstanding voltage		The insulation must not be damaged.		Based on paragraph 7.1 Apply 250% of the rated voltage for 1 to 5s then measure	
Temperature characteristics		Within ± 15%	+ 22, + 82%	The temperature coefficients in paragraph 7.12, table 8, condition B, are based on measurements carried out at 20°C, with no voltage applied.	
Terminal adherence		No detachment or signs of detachment		Based on paragraph 8. 11. 2. Apply 5N for 10 ± 1s in the direction indicated by the arrow.	
	Appearance	There must be no mechanical damage.		Chip is mounted to a board in the	
Resistance to vibration	Rate of capacitance change	Must be within initial tolerance.		manner shown on the right, subjected to vibration (type A in paragraph 8.2),	
	Dissipation factor ($tan\delta$)	Must satisfy initial specified value.		and measured 48 ± 4 hrs. later. Board	
Solderability		At least 3/4 of the surface of the two terminals must be covered with new solder.		Based on paragraph 8. 13 Soldering temperature : 235 \pm 5°C Soldering time : 2 \pm 0.5s	
	Appearance	There must be no mechanical damage.			
	Rate of capacitance change	Within ± 5.0%	Within ± 20.0%	Bd	
Resistance to soldering	Dissipation factor (tanδ)	Must satisfy initial specified value.		Based on paragraph 8. 14. Soldering temperature: 260 ± 5°C	
heat	Insulation resistance	10,000MΩ or 500MΩ \cdot μF, whichever is smaller		Soldering time $: 5 \pm 0.5s$ Preheating $: 5 \pm 0.5s$ $: 150 \pm 10^{\circ}\text{C}$ for 1 to 2 min.	
	Withstanding voltage	The insulation must not be damaged.			
	Appearance	There must be no mechanical damage.			
Temperature	Rate of capacitance change	Within ± 7.5%	Within ± 20.0%	Based on paragraph 9.3 Number of cycles : 5	
cycling	Dissipation factor ($tan\delta$)	Must satisfy initial specified value.		Capacitance measured after 48 ± 4 hrs	
	Insulation resistance	10,000M Ω or 500M Ω · μF, whichever is smaller			
Humidity load test	Appearance	There must be no n	nechanical damage.	Based on paragraph 9.9	
	Rate of capacitance change	± 12.5% or less	Within ± 30.0%	Test temperature: 40 ± 2°C	
	Dissipation factor ($tan\delta$)	5.0% or less	7.5% or less (when rated voltage is 16V: 10.0%)	Relative humidity: 90% to 95% Applied voltage : rated voltage Test time : 500 to 524 hrs.	
	Insulation resistance	500MΩ or 25MΩ \cdot μF, whichever is smaller		Capacitance measured after 48 ± 4	
High- temperature load test	Appearance	There must be no mechanical damage.			
	Rate of capacitance change	Within ± 10.0%	Within ± 30.0%	Based on paragraph 9.10	
	Dissipation factor (tanδ)	5.0% or less	7.5% or less (when rated voltage is 16V: 10.0%)	Test temperature: Max. operating temp Applied voltage : rated voltage × 200% Test time : 1,000 to 1,048 hrs.	
	Insulation resistance	1,000M Ω or 50M Ω · μ F, whichever is smaller		Capacitance measured after 48 ± 4 hr	

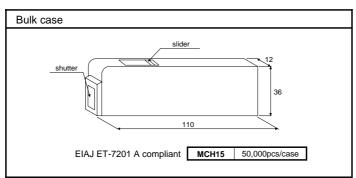
^{*}The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.



Packaging specifications

(Units : mm)





^{*}The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.

Electrical characteristics

■ A (C0G) Characteristics

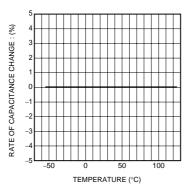


Fig.1 Capacitance-temperature characteristics

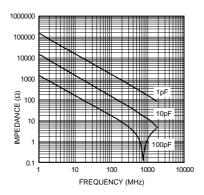


Fig.2 Impedance-frequency characteristics

■ CN (X7R) Characteristics

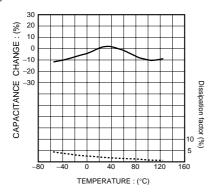


Fig.3 Capacitance-temperature characteristics

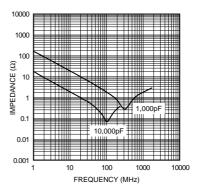


Fig.4 Impedance-frequency characteristics

■FN (Y5V) Characteristics

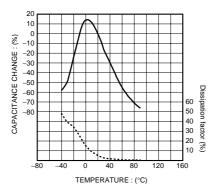


Fig.5 Capacitance-temperature characteristics

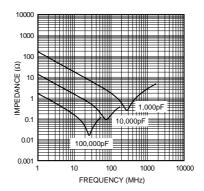
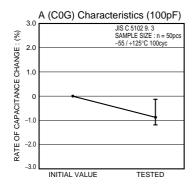


Fig.6 Impedance-frequency characteristics

^{*}The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.

■ Temperature cycling test





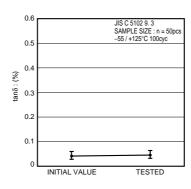


Fig.8 tanδ

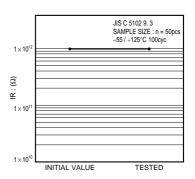


Fig.9 Insulation resistance

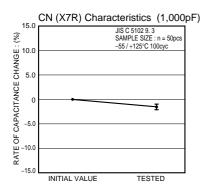


Fig.10 Rate of capacitance change

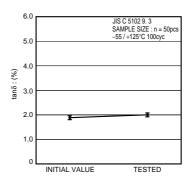


Fig.11 tanδ

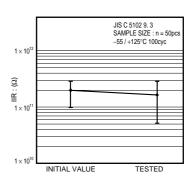


Fig.12 Insulation resistance

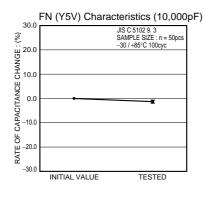


Fig.13 Rate of capacitance change

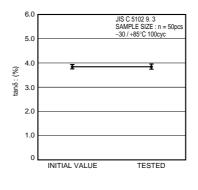


Fig.14 $tan\delta$

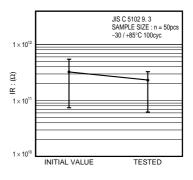


Fig.15 Insulation resistance

^{*}The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.

■ High-temperature load test

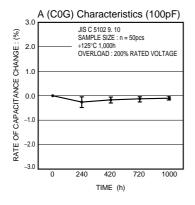


Fig.16 Rate of capacitance change

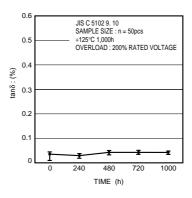


Fig.17 $tan\delta$

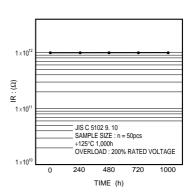


Fig.18 Insulation resistance

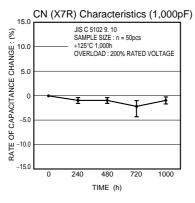


Fig.19 Rate of capacitance change

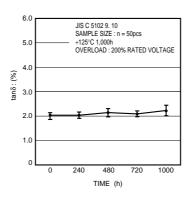


Fig.20 $tan\delta$

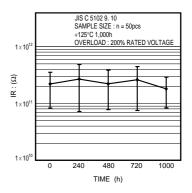


Fig.21 Insulation resistance

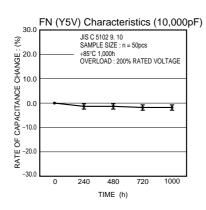


Fig.22 Rate of capacitance change

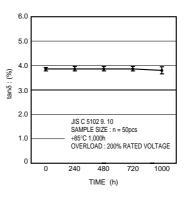


Fig.23 $tan\delta$

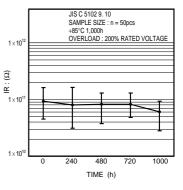


Fig.24 Insulation resistance

^{*}The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.

■ Humidity load test

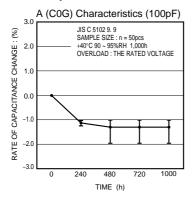


Fig.25 Rate of capacitance change

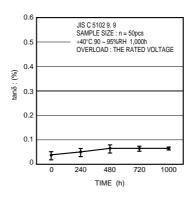


Fig.26 tanδ

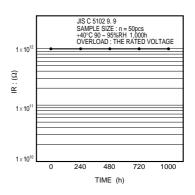


Fig.27 Insulation resistance

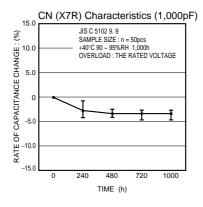


Fig.28 Rate of capacitance change

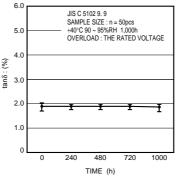


Fig.29 tanδ

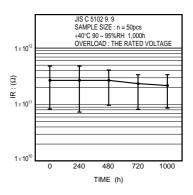


Fig.30 Insulation resistance

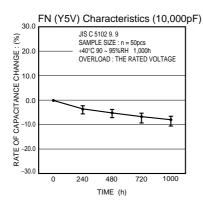


Fig.31 Rate of capacitance change

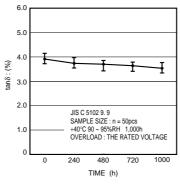


Fig.32 $tan\delta$

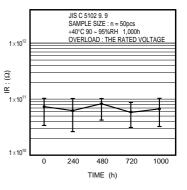


Fig.33 Insulation resistance

^{*}The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.